PCN Number:   20230531000.1   PCN Date:   May 31, 2023																
Customer Contact:         PCN Manager         Dept:         Quality Services           Proposed 1st Ship Date:         Aug 30, 2023         Sample Requests accepted until:         June 30, 2023*           *Sample requests received after June 30, 2023 will not be supported.         *Sample requests received after June 30, 2023 will not be supported.         Wafer Bump Material           Assembly Site         Design         Wafer Bump Material         Wafer Bump Process           Assembly Process         Data Sheet         Wafer Fab Site           Mechanical Specification         Test Site         Wafer Fab Materials           Packing/Shipping/Labeling         Test Process         Wafer Fab Process           PCN Details         Pecking/Shipping/Labeling         Test Process           PCN Details         Description of Change:         Test Process           Wire type         0.8mils Au         0.8mils Cu           Mount compound         1200336111         4226215           Wire type         0.8mils Au	PCN Number: 2023			30531000.1						PCN Date:				May 31, 2023		
Proposed 1st Ship Date:  Aug 30, 2023  *Sample Requests accepted until:  *Sample requests received after June 30, 2023 will not be supported.  Change Type:	Title: Qualification of TI CDAT as an additional Assembly site for select package devices							ackage devices								
*Sample requests received after June 30, 2023 will not be supported.  *Change Type:    Assembly Site	Cus	Customer Contact: PCN Manager Dept: Quality Services														
Change Type:	Proposed 1 <sup>st</sup> Ship Date: Aug					30, 2023							June 30, 2023*			
Assembly Site	*Sa															
Assembly Process	Cha	nge Type:														
Assembly Materials  Mechanical Specification Test Site Wafer Fab Materials Wafer Fab Process  PCDAT A San Additional Asserbly Waferials Wafer Fab Process Waferials Wafer Fab Process Waferials Wafer Fab Process Waferials Wafer Fab Process Waferial	$\boxtimes$	Assembly Site	е				Design	า			□ Wafer I				Bump Material	
Mechanical Specification   Test Site   Wafer Fab Materials   Packing/Shipping/Labeling   Test Process   Wafer Fab Process		Assembly Pro	cess											Wafer	Bump Process	
Packing/Shipping/Labeling Test Process PCN Details  Description of Change:  Texas Instruments Incorporated is announcing the qualification of TI CDAT as an additional Assembly site for select devices. Material differences between sites are as follows:  Group 1 Device:  ASEN TI CDAT Wire type 0.8mils Au 0.8mils Cu Mount compound 1400336111 4226215 Mold compound 1801512111 4222198  Group 2 Device:  JCET TI CDAT Wire type 0.8mils Au 0.8mils Cu Mount compound 120402001600 4226215 Mold compound 120903003709 4222198  Reason for Change:  Continuity of Supply  Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None  Impact on Environmental Ratings  Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental	$\boxtimes$	Assembly Ma	terials											Fab Site		
PCN Details  Description of Change:  Texas Instruments Incorporated is announcing the qualification of TI CDAT as an additional Assembly site for select devices. Material differences between sites are as follows:  Group 1 Device:  ASEN TI CDAT Wire type 0.8mils Au 0.8mils Cu Mount compound 1400336111 4226215 Mold compound 1801512111 4222198  Group 2 Device:  JCET TI CDAT Wire type 0.8mils Au 0.8mils Cu Mount compound 120402001600 4226215 Mold compound 120903003709 4222198  Reason for Change:  Continuity of Supply  Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None  Impact on Environmental Ratings  Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental		Mechanical S	pecific	ation									Fab Materials			
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Assembly site for select devices. Material differences between sites are as follows:    Group 1 Device:	Des	cription of Ch	ange:													
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MSL 2 /260C/1 YEAR SEAL DT

(1P) SN74LS07NSR (a) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

OPT: ITEM:

MSL 1 /235C/UNLIM 03/29/04

### **Group 1 Product Affected:**

INA190A1IRSWR	INA190A2IRSWT	INA190A4IRSWR	INA190A5IRSWT
INA190A1IRSWT	INA190A3IRSWR	INA190A4IRSWT	TMUX154ERSWR
INA190A2IRSWR	INA190A3IRSWT	INA190A5IRSWR	

## **Group 2 Product Affected:**

TS3A5223RSWR

# **Qualification Report**

Approve Date 23-March-2023

#### **Product Attributes**

Attributes	Qual Device: INA190A1IRSWR	Qual Device: INA190A3IRSWR	Qual Device: INA190A5IRSWR	
Assembly Site	CDAT	CDAT	CDAT	
Package Family	UQFN	UQFN	UQFN	
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	
Wafer Fab Supplier	RFAB	RFAB	RFAB	
Wafer Process	LBC8LV	LBC8LV	LBC8LV	

Qual Device INA190A1IRSWR is qualified at MSL1 260C Qual Device INA190A3IRSWR is qualified at MSL1 260C

Qual Device INA190A5IRSWR is qualified at MSL1 260C

#### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Conditions	Qual Device: INA190A1IRSWR	Qual Device: INA190A3IRSWR	Qual Device: INA190A5IRSWR
PC	Preconditioning	Level 1 - 260C	1/308/0	1/308/0	1/308/0
SAM	Post Preconditioning SAM	Level 1 - 260C	1/15/0	1/15/0	1/15/0
UHAST	Unbiased HAST, 110C	264 Hours	1/77/0	1/77/0	1/77/0
SAM	Post Unbiased HAST SAM	Devices	1/5/0	1/5/0	1/5/0
BHAST	Biased HAST, 110C	264 Hours	1/77/0	1/77/0	1/77/0
SAM	Post Biased HAST SAM	Devices	1/5/0	1/5/0	1/5/0
TC	Temperature Cycle, -55/125C	700 Cycles	1/77/0	1/77/0	1/77/0
SAM	Post Temperature Cycle SAM	Devices	1/5/0	1/5/0	1/5/0
HTSL	High Temp Storage Life, 150C	1000 Hours	1/77/0	1/77/0	1/77/0
HTOL	High Temp Op Life, 125C	1000 Hours	1/77/0	1/77/0	1/77/0
SD	Solderability, Pb-Free	155C Dry Bake	1/22/0	1/22/0	1/22/0
MQ	Manufacturability (Assembly)	(per mfg site requirements)	1/PASS	1/PASS	1/PASS
DSS	Die Shear Strength	Die	1/10/0	1/10/0	1/10/0
BBS	Ball Bond Shear	Ball Bonds	1/76/0	1/76/0	1/76/0
WBP	Wire Bond Pull	Wires	1/76/0	1/76/0	1/76/0
VM	Visual Mechanical Inspection	Devices	1/22/0	1/22/0	1/22/0
XR	Internal X-ray	Devices	1/5/0	1/5/0	1/5/0
PD	Physical Dimensions	(per pkg dwg requirements)	1/5/0	1/5/0	1/5/0
CHAR	Electrical Characterization	Devices	1/30/0	1/30/0	1/30/0
MSL	Moisture Sensitivity Level	Level 1 - 260C	1/15/0	1/15/0	1/15/0
YLD	FTY and Bin Summary	Lots	1/PASS	1/PASS	1/PASS

Preconditioning was performed for Unbiased HAST, Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable.

The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1000 Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours.

The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1000 Hours, and 170C/420 Hours.

The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles. Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail					
WW Change Management Team	PCN www admin_team@list.ti.com					

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